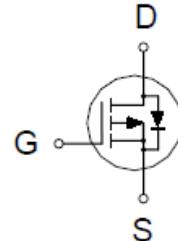
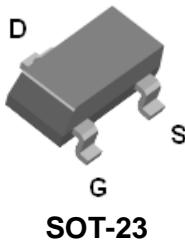


PA504EM

P-Channel Enhancement Mode MOSFET

PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
-40V	150m Ω @ $V_{GS} = -10V$	-1.5A



ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ C$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current $T_A = 25^\circ C$	I_D	-1.5	A
		-1.1	
Pulsed Drain Current ¹	I_{DM}	-9	
Power Dissipation $T_A = 25^\circ C$	P_D	0.5	W
		0.3	
Operating Junction & Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient ²	R_{0JA}		220	°C / W

¹Pulse width limited by maximum junction temperature.

²The value of R_{0JA} is measured with the device mounted on 1in² FR-4 board with 2oz Copper

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ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)

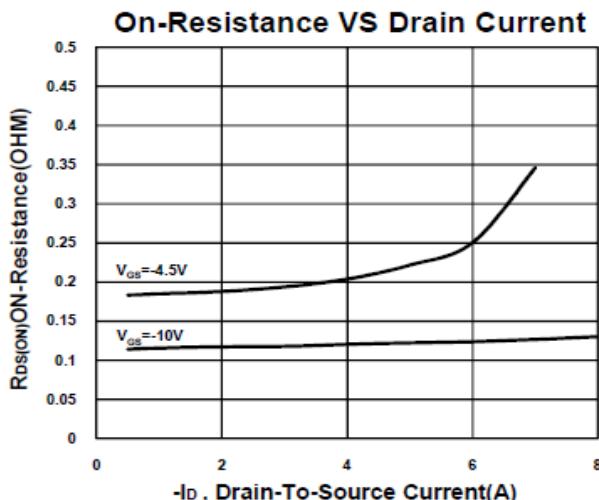
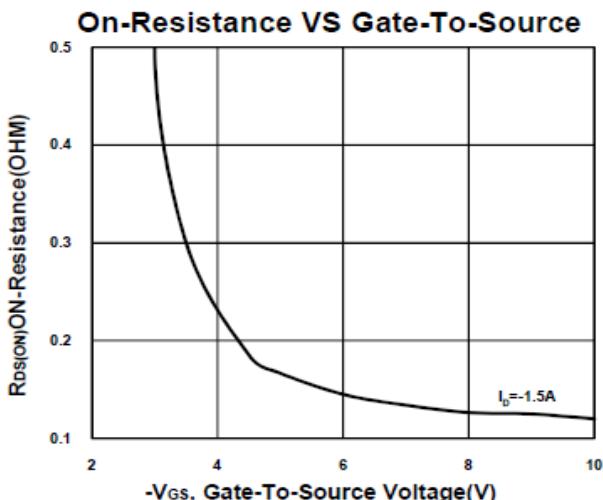
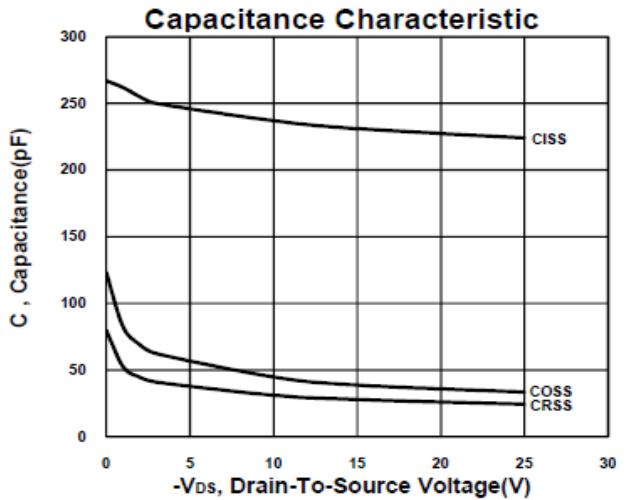
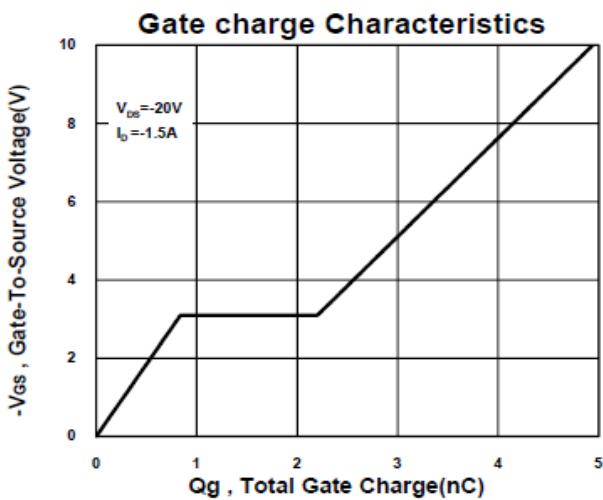
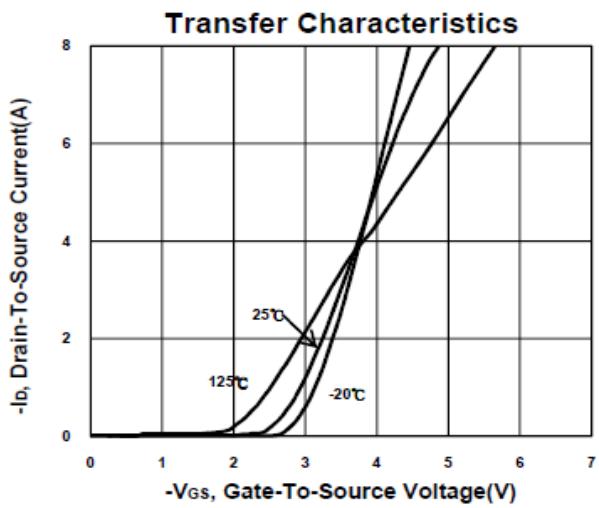
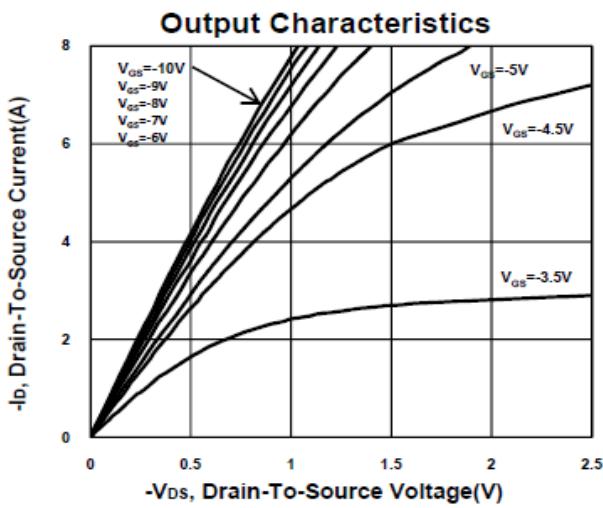
PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = -250\mu\text{A}$	-40			V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = -250\mu\text{A}$	-1.30	-1.8	-3	
Gate-Body Leakage	I_{GSS}	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 20\text{V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = -32\text{V}, V_{\text{GS}} = 0\text{V}$			-1	μA
		$V_{\text{DS}} = -30\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 55^\circ\text{C}$			-10	
On-State Drain Current ¹	$I_{\text{D}(\text{ON})}$	$V_{\text{DS}} = -10\text{V}, V_{\text{GS}} = -4.5\text{V}$	-8			A
Drain-Source On-State Resistance ¹	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}} = -4.5\text{V}, I_D = -1.2\text{A}$		170	250	$\text{m}\Omega$
		$V_{\text{GS}} = -10\text{V}, I_D = -1.5\text{A}$		120	150	
Forward Transconductance ¹	g_{fs}	$V_{\text{DS}} = -5\text{V}, I_D = -1.5\text{A}$		4		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = -20\text{V}, f = 1\text{MHz}$		235		pF
Output Capacitance	C_{oss}			40		
Reverse Transfer Capacitance	C_{rss}			29		
Total Gate Charge ²	Q_g	$V_{\text{DS}} = 0.5V_{(\text{BR})\text{DSS}}, V_{\text{GS}} = -10\text{V}, I_D = -1.5\text{A}$		5.1		nC
Gate-Source Charge ²	Q_{gs}			1		
Gate-Drain Charge ²	Q_{gd}			1.7		
Turn-On Delay Time ²	$t_{\text{d}(\text{on})}$	$V_{\text{DD}} = -20\text{V}$ $I_D \geq -1.5\text{A}, R_G = 6\Omega$		14		nS
Rise Time ²	t_r			6		
Turn-Off Delay Time ²	$t_{\text{d}(\text{off})}$			30		
Fall Time ²	t_f			13		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ\text{C}$)						
Continuous Current	I_S				-0.5	A
Forward Voltage ¹	V_{SD}	$I_F = -1.5\text{A}, V_{\text{GS}} = 0\text{V}$			-1.1	V
Reverse Recovery Time	t_{rr}	$I_F = -3\text{A}, dI_F/dt = 100\text{A}/\mu\text{s}$		13		nS
Reverse Recovery Charge	Q_{rr}			7		nC

¹Pulse test : Pulse Width $\leq 300\ \mu\text{sec}$, Duty Cycle $\leq 2\%$.

²Independent of operating temperature.

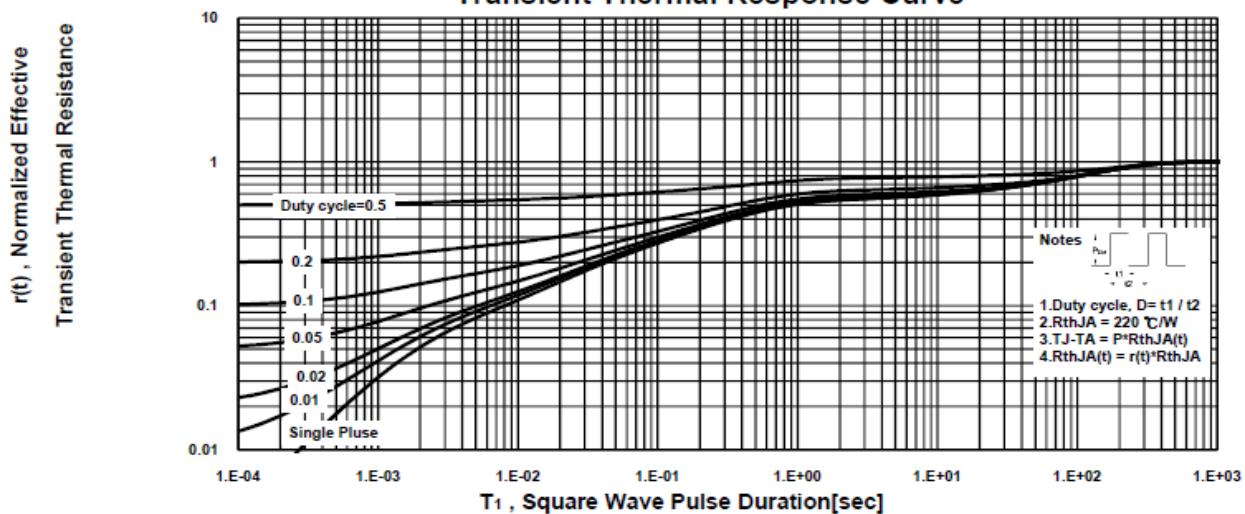
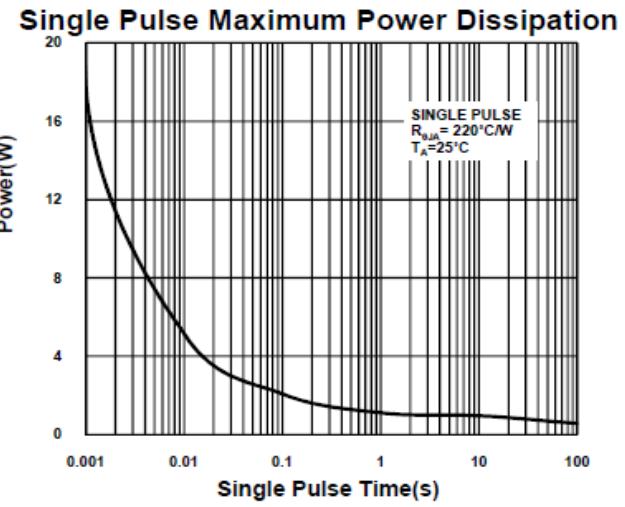
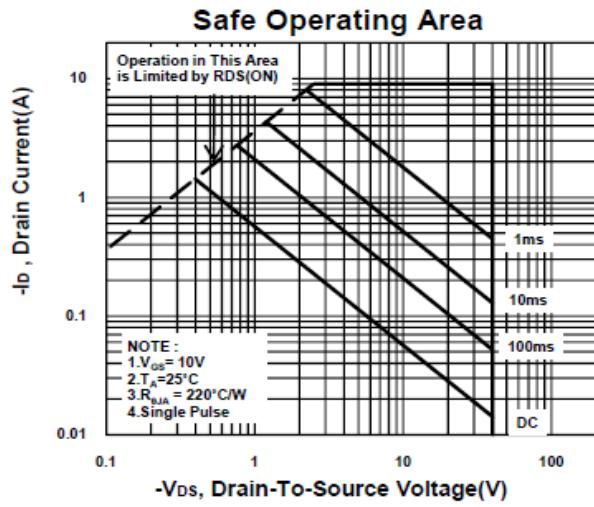
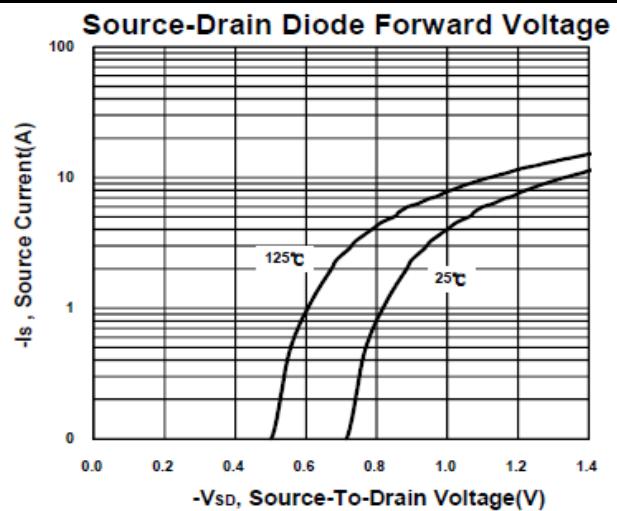
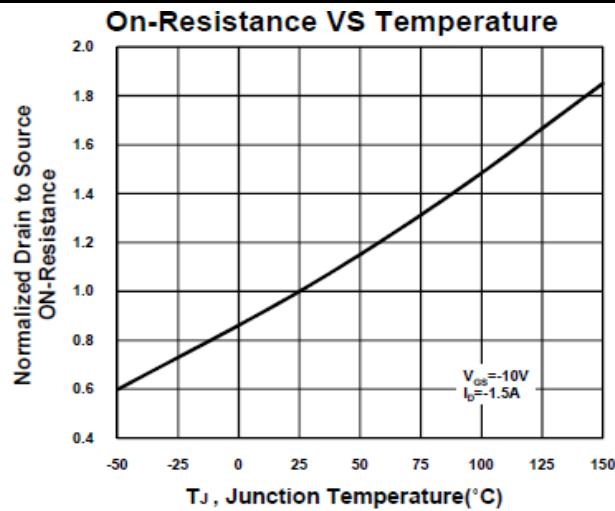
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Package Dimension

SOT-23-3 MECHANICAL DATA

Dimension	mm			Dimension	mm		
	Min.	Typ.	Max.		Min.	Typ.	Max.
A		1.05		H	0.1		0.2
B	2.4		3	I	0.3		0.6
C	1.4		1.73				
D	2.7		3.1				
E	1		1.31				
F	0		0.15				
G	0.3		0.5				

